



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Stefan Fliss  
Serial No. : 10/660,790  
Filed : September 12, 2003  
Title : APPARATUS FOR MONITORING THE FUNCTIONALITY OF AN OPTICAL  
ELEMENT

Art Unit : Unknown

Examiner : Unknown

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Copies of the references listed on the attached form PTO-1449 are enclosed. A copy of a communication from a foreign patent office in a counterpart application is also enclosed.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 10/8/03

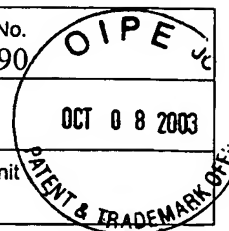


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Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 15540-011001	Application No. 10/660,790
	Applicant Stefan Fliss			
	Filing Date September 12, 2003	Group Art Unit		



U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,691,106	Sept. 1, 1987	Hyun et al.			

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AB	Dowden, S. et al., "Reflectometer for fast measurements of mirror reflectivity," Measurement Science and Technology, IOP Publishing, Bristol, GB, Bd. 8, Nr. 11, pp. 1258-1261 (1997).
	AC	Takahashi H. et al., "Automatic reflectivity map measurement of high power CO <sub>2</sub> laser optics," Optics and Laser Technology, Elsevier Science Publishers BV., Amsterdam, NL, Bd. 21, Nr. 1, pp. 37-39 (1989).

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	